

<b>Notice of References Cited</b>	Application/Control No. 10/701,479		Applicant(s)/Patent Under Reexamination SUNTER ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,513,186	04-1996	Levitt, Marc E.	714/727
*	B	US-6,499,124	12-2002	Jacobson, Neil G.	714/727
*	C	US-6,925,583	08-2005	Khu et al.	714/30
*	D	US-5,872,796	02-1999	Golshan et al.	714/727
*	E	US-5,744,949	04-1998	Whetsel, Lee D.	324/158.1
*	F	US-5,656,953	08-1997	Whetsel, Lee D.	326/83
*	G	US-6,000,051	12-1999	Nadeau-Dostie et al.	714/727
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	IEEE Standard Test Access Port and Boundary-Scan Architecture; IEEE Std1149.1-1990.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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